							REVIS	IONS										
LTR				DES	SCRIPTI	NC					DA	ATE (Y	R-MO-I	DA)		APPF	ROVED	)
А	Drawing up	odated to	o reflect c	urrent r	equireme	ents	o					02-0	)3-18			R. M	ONNIN	
В	Five year r	eview re	quiremen	trrp								09-1	0-21			C. S	AFFLE	
REV																		
SHEET																		
REV																		
SHEET																		
REV STATUS			REV		В	В	В	В	В	В	В	В	В	В	В			
OF SHEETS			SHEET	-	1	2	3	4	5	6	7	8	9	10	11			
PMIC N/A	NDARD		PREPARED BY RICK OFFICER					DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS. OHIO 43218-3990										
MICRC DRA	CIRCUIT		RAJ	ESH P	ITHADIA						http	)://wv	/w.ds	scc.dl	a.mil			
THIS DRAWIN FOR US DEPAR	NG IS AVAILA SE BY ALL RTMENTS	ABLE	APPRC MIC	OVED E CHAEL	3Y FRYE			MICROCIRCUIT, LINEAR, LOGARITHMIC AMPLIFIER, MONOLITHIC SILICON										
AND AGEN DEPARTMEN	NCIES OF TH	IE NSE	DRAWI	NG API 95-05	PROVAL 5-12	DATE												
AM	SC N/A		REVISI	ON LE\	VEL B			S	ZE A	CA	GE CC 67268	DE B		ļ	5962-	-9559	8	
								SHE	ΕI		1	OF	11					

# 1. SCOPE

1.1 <u>Scope</u>. This drawing documents two product assurance class levels consisting of high reliability (device classes Q and M) and space application (device class V). A choice of case outlines and lead finishes are available and are reflected in the Part or Identifying Number (PIN). When available, a choice of Radiation Hardness Assurance (RHA) levels is reflected in the PIN.

1.2 <u>PIN</u>. The PIN is as shown in the following example:



1.2.1 <u>RHA designator</u>. Device classes Q and V RHA marked devices meet the MIL-PRF-38535 specified RHA levels and are marked with the appropriate RHA designator. Device class M RHA marked devices meet the MIL-PRF-38535, appendix A specified RHA levels and are marked with the appropriate RHA designator. A dash (-) indicates a non-RHA device.

1.2.2 <u>Device type(s)</u>. The device type(s) identify the circuit function as follows:

Device type	<u>Generic number</u>	Circuit function
01	AD641	Logarithmic amplifier

1.2.3 <u>Device class designator</u>. The device class designator is a single letter identifying the product assurance level as follows:

	Device class		Device requirem	ents documentation
	М	Vendor self- JAN class le	certification to the re evel B microcircuits i	equirements for MIL-STD-883 compliant, non- in accordance with MIL-PRF-38535, appendix A
	Q or V	Certification	and qualification to	MIL-PRF-38535
1.2.4	Case outline(s).	The case outline(s) are as designate	ated in MIL-STD-183	35 and as follows:
	Outline letter	Descriptive designator	Terminals	Package style

R	GDIP1-T20 or CDIP2-T20	20	Dual-in-line

1.2.5 <u>Lead finish</u>. The lead finish is as specified in MIL-PRF-38535 for device classes Q and V or MIL-PRF-38535, appendix A for device class M.

STANDARD MICROCIRCUIT DRAWING	SIZE A		5962-95598
DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43218-3990		REVISION LEVEL B	SHEET 2

1.3 Absolute maximum ratings. 1/

Supply voltage (±V <sub>S</sub> )	±7.5 V
Input voltage (SIG -IN pin or SIG +IN pin to GND)	-3 V to +300 mV
Attenuator input voltage (ATN IN pin to ATN COM pins)	±4 V
Power dissipation (PD)	900 mW
Storage temperature range	-65°C to +150°C
Lead temperature (soldering, 10 seconds)	300°C
Thermal resistance, junction-to-case ( $\theta_{JC})$	25°C/W
Thermal resistance, junction-to-ambient ( $\theta_{JA}$ )	120°C/W

1.4 Recommended operating conditions.

Positive operating voltage range (+V <sub>S</sub> )	4.5 V to 5.5 V
Negative operating voltage range $(-V_S)$	-4.5 V to -5.5 V
Ambient operating temperature range (T <sub>A</sub> )	-55°C to +125°C

### 2. APPLICABLE DOCUMENTS

2.1 <u>Government specification, standards, and handbooks</u>. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

# DEPARTMENT OF DEFENSE SPECIFICATION

MIL-PRF-38535 - Integrated Circuits, Manufacturing, General Specification for.

### DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883	-	Test Method Standard Microcircuits.
MIL-STD-1835	-	Interface Standard Electronic Component Case Outlines.

### DEPARTMENT OF DEFENSE HANDBOOKS

MIL-HDBK-103 - List of Standard Microcircuit Drawings.

MIL-HDBK-780 - Standard Microcircuit Drawings.

(Copies of these documents are available online at <u>http://assist.daps.dla.mil/quicksearch/</u> or from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 <u>Order of precedence</u>. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

1/ Stresses above the absolute maximum rating may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.

STANDARD MICROCIRCUIT DRAWING	SIZE A		5962-95598
DEFENSE SUPPLY CENTER COLUMBUS		REVISION LEVEL	SHEET
COLUMBUS, OHIO 43218-3990		B	3

### 3. REQUIREMENTS

3.1 <u>Item requirements</u>. The individual item requirements for device classes Q and V shall be in accordance with MIL-PRF-38535 and as specified herein or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein. The individual item requirements for device class M shall be in accordance with MIL-PRF-38535, appendix A for non-JAN class level B devices and as specified herein.

3.2 <u>Design, construction, and physical dimensions</u>. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535 and herein for device classes Q and V or MIL-PRF-38535, appendix A and herein for device class M.

3.2.1 Case outlines. The case outline shall be in accordance with 1.2.4 herein.

3.2.2 <u>Terminal connections</u>. The terminal connections shall be as specified on figure 1.

3.2.3 Block diagram. The block diagram shall be as specified on figure 2.

3.3 <u>Electrical performance characteristics and postirradiation parameter limits</u>. Unless otherwise specified herein, the electrical performance characteristics and postirradiation parameter limits are as specified in table I and shall apply over the full ambient operating temperature range.

3.4 <u>Electrical test requirements</u>. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are defined in table I.

3.5 <u>Marking</u>. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked. For packages where marking of the entire SMD PIN number is not feasible due to space limitations, the manufacturer has the option of not marking the "5962-" on the device. For RHA product using this option, the RHA designator shall still be marked. Marking for device classes Q and V shall be in accordance with MIL-PRF-38535. Marking for device class M shall be in accordance with MIL-PRF-38535, appendix A.

3.5.1 <u>Certification/compliance mark</u>. The certification mark for device classes Q and V shall be a "QML" or "Q" as required in MIL-PRF-38535. The compliance mark for device class M shall be a "C" as required in MIL-PRF-38535, appendix A.

3.6 <u>Certificate of compliance</u>. For device classes Q and V, a certificate of compliance shall be required from a QML-38535 listed manufacturer in order to supply to the requirements of this drawing (see 6.6.1 herein). For device class M, a certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-HDBK-103 (see 6.6.2 herein). The certificate of compliance submitted to DSCC-VA prior to listing as an approved source of supply for this drawing shall affirm that the manufacturer's product meets, for device classes Q and V, the requirements of MIL-PRF-38535 and herein or for device class M, the requirements of MIL-PRF-38535, appendix A and herein.

3.7 <u>Certificate of conformance</u>. A certificate of conformance as required for device classes Q and V in MIL-PRF-38535 or for device class M in MIL-PRF-38535, appendix A shall be provided with each lot of microcircuits delivered to this drawing.

3.8 <u>Notification of change for device class M</u>. For device class M, notification to DSCC-VA of change of product (see 6.2 herein) involving devices acquired to this drawing is required for any change that affects this drawing.

3.9 <u>Verification and review for device class M</u>. For device class M, DSCC, DSCC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

3.10 <u>Microcircuit group assignment for device class M</u>. Device class M devices covered by this drawing shall be in microcircuit group number 49 (see MIL-PRF-38535, appendix A).

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS	SIZE A		5962-95598
DEFENSE SUPPLY CENTER COLUMBUS		REVISION LEVEL	SHEET
COLUMBUS, OHIO 43218-3990		B	4

	T.	ABLE I. <u>Electrical per</u>	formance	e characte	eristics	<u>3</u> .			
Test	Symbol	$Conditions \\ -55^{\circ}C \leq T_A \leq +12 \\ unless otherwise space$	25°C becified	Group A subgroups		Device type	Limits		Unit
							Min	Max	
Total absolute dc accuracy	ТА	I <sub>OUT</sub> = 1 mA x log <sub>10</sub> ( V <sub>IN</sub>   / 1 mV)	)	1		01	-0.9	0.9	dB
		$V_{IN} = \pm 1 \text{ mV to } \pm 100$	) mV	2,3			-1.8	1.8	
		I <sub>OUT</sub> = 1 mA x log <sub>10</sub> ( V <sub>IN</sub>   / 1 mV)	)	1			-1.5	1.5	
		V <sub>IN</sub> = ±1 mV to ±100 using attenuator	) mV,	2,3			-2.0	2.0	
Total absolute dc accuracy transfer function versus supplies	ТА	$\pm V_{S} = \pm 4.5 \text{ V to } \pm 7.5$ $I_{OUT} = 1 \text{ mA x } \log_{10}$ $( V_{IN}  / 1 \text{ mV})$ $V_{IN} = \pm 1 \text{ mV to } \pm 100$ $T_{A} = \pm 25^{\circ}\text{C}$	5 V, ) ), ) mV,	1		01	-1.0	1.0	dB
DC linearity	LEdc	$V_{IN} = \pm 1 \text{ mV to } \pm 100$ $T_A = \pm 25^{\circ}\text{C}$	0 mV,	1		01	-0.6	0.6	dB
Input offset voltage	V <sub>OS</sub>	Differential		1		01	-200	200	μV
				2,3			-300	300	
Slope current	IYdc	At dc		1,2,3	3	01	0.98	1.02	mA
Slope current versus supplies	lYdc	$\pm V_{S} = \pm 4.5 \text{ V to } \pm 7.5$ T <sub>A</sub> = +25°C	5 V,	1		01	-0.4	0.4	%V
Intercept voltage	VXdc	At dc		1		01	0.95	1.05	mV
				2,3			0.90	1.10	
		Using attenuator, $T_A = +25^{\circ}C$		1			9.0	11.0	
Application resistors	R <sub>A</sub>			1		01	995	1005	Ω
				2,3			990	1010	
STAN MICROCIRC	IDARD JIT DRAW	/ING	SIZ A	ZE <b>A</b>				596	2-95598
DEFENSE SUPPLY COLUMBUS, C	CENTER CO HIO 43218-3	DLUMBUS 3990			REVI	SION LEVE B	L	SHEET	5

Test	Symbol	$\label{eq:conditions} Conditions \\ -55^{\circ}C \leq T_A \leq +125^{\circ}C \\ \text{unless otherwise specified}$	Group A subgroups	Device type	Limits		Unit
					Min	Max	-
Supply current	+IS	+V <sub>S</sub> = 5.0 V, static conditions	1,2,3	01		15.0	mA
	-IS	$-V_S = -5.0 V$ , static conditions				60.0	
Log conformance (ac linearity)	LEac	Single configuration <u>1</u> / frequency = 250 MHz, Input level = -44 dBm to 0 dBm	4	01	-2.0	2.0	dB
		Single configuration <u>1</u> / frequency = 250 MHz, Input level = -42 dBm to -4 dBm	5,6		-2.5	2.5	
		Dual configuration <u>1</u> / frequency = 250 MHz, Input level = -60 dBm to -2 dBm	4		-2.0	2.0	
		-2  dBm       Dual configuration 1/ $5,6$ frequency = 250 MHz,       Input level = -56 dBm to $-4  dBm$	2.5				
AC slope current	IYac	$f \le 1 \text{ MHz}, \qquad \underline{1}/\underline{2}/$ T <sub>A</sub> = +25°C	4	01	0.98	1.02	mA
		$f = 30 \text{ MHz}, \frac{1}{2}$ T <sub>A</sub> = +25°C	•		0.91	0.97	-
		$f = 60 \text{ MHz}, \frac{1}{2}$ $T_A = +25^{\circ}\text{C}$	•		0.86	0.94	-
AC intercept voltage	VXac	f = 250 MHz <u>1</u> /	4	01	-40.84	-39.96	dBm
			5,6		-40.59	-39.47	
<ul> <li>If not tested, shall be g</li> <li>The slope is measured</li> </ul>	uaranteed to the tot the the tot the tot the tot the tot to the tot to the tot tot tot tot tot tot tot tot tot to	he limits specified in table I her	ein. ansfer function.				

STANDARD MICROCIRCUIT DRAWING	SIZE A		5962-95598
DEFENSE SUPPLY CENTER COLUMBUS		REVISION LEVEL	SHEET
COLUMBUS, OHIO 43218-3990		B	6

Device type	01		
Case outline	R		
Terminal	Terminal symbol		
1	SIGNAL –INPUT (SIG –IN)		
2	ATTENUATOR LOW (ATN LO)		
3	ATTENUATOR COMMON (ATN COM)		
4	ATTENUATOR COMMON (ATN COM)		
5	ATTENUATOR INPUT (ATN IN)		
6	BALANCE LIMITER 1 (BL1)		
7	NEGATIVE POWER SUPPLY (-V <sub>S</sub> )		
8	INTERNAL TEMPERATURE COMPENSATION (ITC)		
9	BALANCE LIMITER 2 (BL2)		
10	SIGNAL –OUTPUT (SIG –OUT)		
11	SIGNAL +OUTPUT (SIG +OUT)		
12	POSITIVE POWER SUPPLY (+V <sub>S</sub> )		
13	LOGARITHMIC COMMON (LOG COM)		
14	LOGARITHMIC OUTPUT (LOG OUT)		
15	GAIN RESISTOR 2 (RG2)		
16	GAIN RESISTOR 0 (RG0)		
17	GAIN RESISTOR 1 (RG1)		
18	CIRCUIT COMMON (CKT COM)		
19	ATTENUATOR OUTPUT (ATN OUT)		
20	SIGNAL +INPUT (SIG +IN)		

FIGURE 1. Terminal connections.

STANDARD MICROCIRCUIT DRAWING	SIZE A		5962-95598
DEFENSE SUPPLY CENTER COLUMBUS		REVISION LEVEL	SHEET
COLUMBUS, OHIO 43218-3990		B	7



### 4. VERIFICATION

4.1 <u>Sampling and inspection</u>. For device classes Q and V, sampling and inspection procedures shall be in accordance with MIL-PRF-38535 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein. For device class M, sampling and inspection procedures shall be in accordance with MIL-PRF-38535, appendix A.

4.2 <u>Screening</u>. For device classes Q and V, screening shall be in accordance with MIL-PRF-38535, and shall be conducted on all devices prior to qualification and technology conformance inspection. For device class M, screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection.

### 4.2.1 Additional criteria for device class M.

- a. Burn-in test, method 1015 of MIL-STD-883.
  - (1) Test condition A, B, C, D, or E. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.
  - (2)  $T_A = +125^{\circ}C$ , minimum.
- b. Interim and final electrical test parameters shall be as specified in table II herein.

# 4.2.2 Additional criteria for device classes Q and V.

- a. The burn-in test duration, test condition and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document revision level control of the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.
- b. Interim and final electrical test parameters shall be as specified in table II herein.
- c. Additional screening for device class V beyond the requirements of device class Q shall be as specified in MIL-PRF-38535, appendix B.

4.3 <u>Qualification inspection for device classes Q and V</u>. Qualification inspection for device classes Q and V shall be in accordance with MIL-PRF-38535. Inspections to be performed shall be those specified in MIL-PRF-38535 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.4).

4.4 <u>Conformance inspection</u>. Technology conformance inspection for classes Q and V shall be in accordance with MIL-PRF-38535 including groups A, B, C, D, and E inspections and as specified herein. Quality conformance inspection for device class M shall be in accordance with MIL-PRF-38535, appendix A and as specified herein. Inspections to be performed for device class M shall be those specified in method 5005 of MIL-STD-883 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.4).

### 4.4.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 7, 8, 9, 10, and 11 in table I, method 5005 of MIL-STD-883 shall be omitted.

4.4.2 Group C inspection. The group C inspection end-point electrical parameters shall be as specified in table II herein.

STANDARD MICROCIRCUIT DRAWING	SIZE A		5962-95598
DEFENSE SUPPLY CENTER COLUMBUS		REVISION LEVEL	SHEET
COLUMBUS, OHIO 43218-3990		B	9

<b>-</b> · · · ·	0.1		
l est requirements	Subgroups	Subgroups	
	(in accordance with	(in accordance with	
	MIL-STD-883,	MIL-PRF-38	535, table III)
	method 5005, table I)		. ,
	Device	Device	Device
	class M	class Q	class V
Interim electrical	1	1	1
parameters (see 4.2)			
Final electrical	1,2,3 <u>1</u> /	1,2,3 <u>1</u> /	1,2,3 <u>1</u> /
parameters (see 4.2)			
Group A test	1,2,3,4,5,6 <u>2</u> /	1,2,3,4,5,6 <u>2</u> /	1,2,3, <u>2</u> /
requirements (see 4.4)			4,5,6
Group C end-point electrical	1	1	1,2,3
parameters (see 4.4)			
Group D end-point electrical	1	1	1,2,3
parameters (see 4.4)			
Group E end-point electrical			
parameters (see 4.4)			

# TABLE II. Electrical test requirements.

1/ PDA applies to subgroup 1.

2/ Subgroups 4, 5, 6, if not tested, shall be guaranteed to the limits specified in table I.

4.4.2.1 Additional criteria for device class M. Steady-state life test conditions, method 1005 of MIL-STD-883:

- a. Test condition A, B, C, D, or E. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.
- b.  $T_A = +125^{\circ}C$ , minimum.
- c. Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

4.4.2.2 Additional criteria for device classes Q and V. The steady-state life test duration, test condition and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The test circuit shall be maintained under document revision level control by the device manufacturer's TRB in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.

4.4.3 Group D inspection. The group D inspection end-point electrical parameters shall be as specified in table II herein.

4.4.4 <u>Group E inspection</u>. Group E inspection is required only for parts intended to be marked as radiation hardness assured (see 3.5 herein).

- a. End-point electrical parameters shall be as specified in table II herein.
- b. For device classes Q and V, the devices or test vehicle shall be subjected to radiation hardness assured tests as specified in MIL-PRF-38535 for the RHA level being tested. For device class M, the devices shall be subjected to radiation hardness assured tests as specified in MIL-PRF-38535, appendix A for the RHA level being tested. All device classes must meet the post irradiation end-point electrical parameter limits as defined in table I at T<sub>A</sub> = +25°C ±5°C, after exposure, to the subgroups specified in table II herein.

STANDARD MICROCIRCUIT DRAWING	SIZE A		5962-95598
DEFENSE SUPPLY CENTER COLUMBUS		REVISION LEVEL	SHEET
COLUMBUS, OHIO 43218-3990		B	10

# 5. PACKAGING

5.1 <u>Packaging requirements</u>. The requirements for packaging shall be in accordance with MIL-PRF-38535 for device classes Q and V or MIL-PRF-38535, appendix A for device class M.

# 6. NOTES

6.1 <u>Intended use</u>. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.1.1 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractor prepared specification or drawing.

6.1.2 <u>Substitutability</u>. Device class Q devices will replace device class M devices.

6.2 <u>Configuration control of SMD's</u>. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished using DD Form 1692, Engineering Change Proposal.

6.3 <u>Record of users</u>. Military and industrial users should inform Defense Supply Center Columbus (DSCC) when a system application requires configuration control and which SMD's are applicable to that system. DSCC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DSCC-VA, telephone (614) 692-0544.

6.4 <u>Comments</u>. Comments on this drawing should be directed to DSCC-VA, Columbus, Ohio 43218-3990, or telephone (614) 692-0547.

6.5 <u>Abbreviations, symbols, and definitions</u>. The abbreviations, symbols, and definitions used herein are defined in MIL-PRF-38535 and MIL-HDBK-1331.

### 6.6 Sources of supply.

6.6.1 <u>Sources of supply for device classes Q and V</u>. Sources of supply for device classes Q and V are listed in QML-38535. The vendors listed in QML-38535 have submitted a certificate of compliance (see 3.6 herein) to DSCC-VA and have agreed to this drawing.

6.6.2 <u>Approved sources of supply for device class M</u>. Approved sources of supply for class M are listed in MIL-HDBK-103. The vendors listed in MIL-HDBK-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DSCC-VA.

STANDARD MICROCIRCUIT DRAWING	SIZE A		5962-95598
DEFENSE SUPPLY CENTER COLUMBUS		REVISION LEVEL	SHEET
COLUMBUS, OHIO 43218-3990		B	11

#### STANDARD MICROCIRCUIT DRAWING BULLETIN

### DATE: 09-10-21

Approved sources of supply for SMD 5962-95598 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38535 during the next revision. MIL-HDBK-103 and QML-38535 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DSCC-VA. This information bulletin is superseded by the next dated revision of MIL-HDBK-103 and QML-38535. DSCC maintains an online database of all current sources of supply at <a href="http://www.dscc.dla.mil/Programs/Smcr/">http://www.dscc.dla.mil/Programs/Smcr/</a>.

Standard	Vendor	Vendor
microcircuit drawing	CAGE	similar
PIN 1/	number	PIN 2/
5962-9559801MRA	24355	AD641SQ

- <u>1</u>/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the vendor to determine its availability.
- <u>2</u>/ <u>Caution</u>. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number Vendor name and address

24355

Analog Devices Route 1 Industrial Park P.O. Box 9106 Norwood, MA 02062 Point of contact: 804 Woburn Street Wilmington, MA 01887-3462

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in the information bulletin.